




# Power MOSFETS


## DATASHEET


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**LM20081PLI8A**

P-Channel  
Enhancement Mode MOSFET

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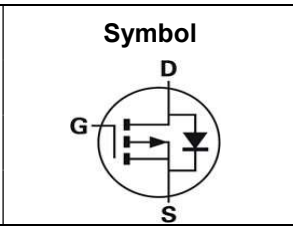
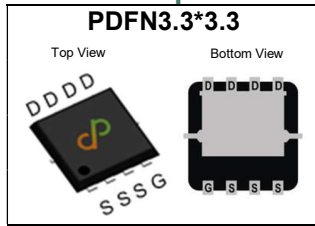


Quality Management Systems

ISO 9001:2015 Certificate

## P-Channel Enhancement Mode MOSFET

### Pin Description



### Product Summary

Symbol	P-Channel	Unit
$V_{DSS}$	-20	V
$R_{DS(ON)-Max}$	7.2	m $\Omega$
$I_D$	-68	A

### Feature

- Reliable and Rugged
- ROHS Compliant & Halogen-Free
- 100% UIS and Rg Tested

### Applications

- Portable Equipment
- Load switch

### Ordering Information

Orderable Part Number	Package Type	Form	Shipping	Marking
LM20081PLI8A	PDFN3.3*3.3	Tape & Reel	5000 / Tape & Reel	20081 □□□□□□

Note : □□□□□□ = Lot Code

### Absolute Maximum Ratings (T<sub>J</sub>=25°C Unless Otherwise Noted)

Symbol	Parameter	P-Channel	Unit
$V_{DSS}$	Drain-Source Voltage	-20	V
$V_{GSS}$	Gate-Source Voltage	±12	
$T_J$	Maximum Junction Temperature	150	°C
$T_{STG}$	Storage Temperature Range	-55 to 150	°C
$I_S$	Diode Continuous Forward Current	$T_C=25^\circ C$ -30	A
$I_{DM}^{①}$	Pulse Drain Current Tested	$T_A=25^\circ C$ -270	A
$I_D$	Continuous Drain Current	$T_C=25^\circ C$ -68	A
		$T_C=100^\circ C$ -43	
$P_D$	Maximum Power Dissipation	$T_C=25^\circ C$ 33	W
		$T_C=100^\circ C$ 13.2	
$I_D$	Continuous Drain Current	$T_A=25^\circ C$ -15	A
		$T_A=70^\circ C$ -12	
$P_D$	Maximum Power Dissipation	$T_A=25^\circ C$ 1.6	W
		$T_A=70^\circ C$ 1.1	
$I_{AS}^{②}$	Avalanche Current, Single pulse	L=0.1mH -31	A
		L=0.5mH -16	
$E_{AS}^{②}$	Avalanche Energy, Single pulse	L=0.1mH 48	A
		L=0.5mH 65	

### Thermal Characteristics

Symbol	Parameter	Rating	Unit
$R_{\theta JC}$	Thermal Resistance-Junction to Case	Steady State	3.8 °C/W
$R_{\theta JA}^{③}$	Thermal Resistance-Junction to Ambient	Steady State	76 °C/W

Note ① : Max. current is limited by junction temperature

Note ② : UIS tested and pulse width are limited by maximum junction temperature 150°C

Note ③ : Surface Mounted on 1in<sup>2</sup> FR-4 board with 1oz.

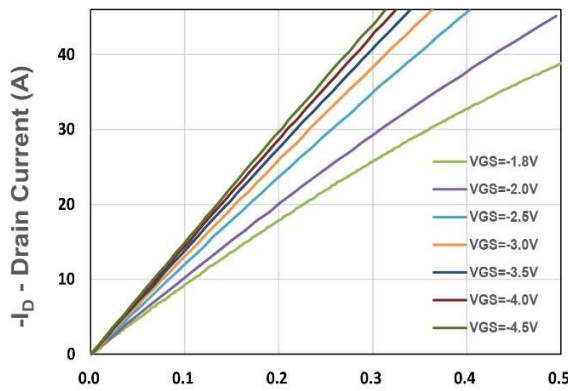
## P-Channel Electrical Characteristics (T<sub>J</sub>=25°C Unless Otherwise Noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
<b>Static Electrical Characteristics</b>						
<b>BV<sub>DSS</sub></b>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>DS</sub> =-250uA	-20	-	-	V
<b>I<sub>DSS</sub></b>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =-16V, V <sub>GS</sub> =0V	-	-	-1	uA
<b>V<sub>GS(th)</sub></b>	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>DS</sub> =-250uA	-0.4	-0.7	-1	V
<b>I<sub>GSS</sub></b>	Gate Leakage Current	V <sub>GS</sub> =±12V, V <sub>DS</sub> =0V	-	-	±100	nA
<b>R<sub>DS(ON)</sub></b> <sup>④</sup>	Drain-Source On-state Resistance	V <sub>GS</sub> =-4.5V, I <sub>DS</sub> =-10A	-	6	7.2	mΩ
		V <sub>GS</sub> =-2.5V, I <sub>DS</sub> =-8A	-	7.8	10.5	
		V <sub>GS</sub> =-1.8V, I <sub>DS</sub> =-6A	-	10	15	
<b>gfs</b>	Forward Transconductance	V <sub>DS</sub> =-5V, I <sub>DS</sub> =-5A	-	30	-	S
<b>Dynamic Characteristics</b> <sup>⑤</sup>						
<b>R<sub>G</sub></b>	Gate Resistance	V <sub>GS</sub> =0V, V <sub>DS</sub> =0V, Freq.=1MHz	-	8.5	-	Ω
<b>C<sub>iss</sub></b>	Input Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =-10V, Freq.=1MHz	-	4135	-	pF
<b>C<sub>oss</sub></b>	Output Capacitance		-	618	-	
<b>C<sub>rss</sub></b>	Reverse Transfer Capacitance		-	390	-	
<b>td(ON)</b>	Turn-on Delay Time	V <sub>GS</sub> =-4.5V, V <sub>DS</sub> =-15V, I <sub>D</sub> =-1A, R <sub>GEN</sub> =6Ω	-	11.9	-	nS
<b>t<sub>r</sub></b>	Turn-on Rise Time		-	22.1	-	
<b>t<sub>d(OFF)</sub></b>	Turn-off Delay Time		-	142.1	-	
<b>t<sub>f</sub></b>	Turn-off Fall Time		-	274.5	-	
<b>Q<sub>g</sub></b>	Total Gate Charge	V <sub>GS</sub> =-2.5V, V <sub>DS</sub> =-10V I <sub>D</sub> =-10A	-	28.7	-	nC
<b>Q<sub>g</sub></b>	Total Gate Charge	V <sub>GS</sub> =-4.5V, V <sub>DS</sub> =-10V, I <sub>D</sub> =-10A	-	48.1	-	
<b>Q<sub>gs</sub></b>	Gate-Source Charge		-	8.05	-	
<b>Q<sub>gd</sub></b>	Gate-Drain Charge		-	10	-	
<b>Source-Drain Characteristics</b>						
<b>V<sub>SD</sub></b> <sup>④</sup>	Diode Forward Voltage	I <sub>SD</sub> =-5A, V <sub>GS</sub> =0V	-	-0.65	-1.1	V
<b>t<sub>rr</sub></b>	Reverse Recovery Time	I <sub>F</sub> =-5A, V <sub>R</sub> =-10V	-	41.3	-	nS
<b>Q<sub>rr</sub></b>	Reverse Recovery Charge	di <sub>F</sub> /dt=100A/μs	-	32	-	nC

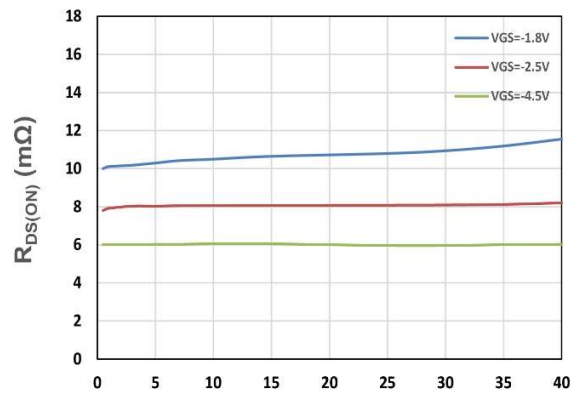
Note ④ : Pulse test (pulse width≤300us, duty cycle≤2%).

Note ⑤ : Guaranteed by design, not subject to production testing.

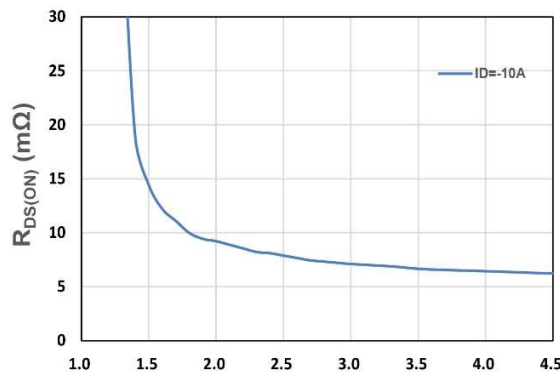
## P-Channel Typical Characteristics



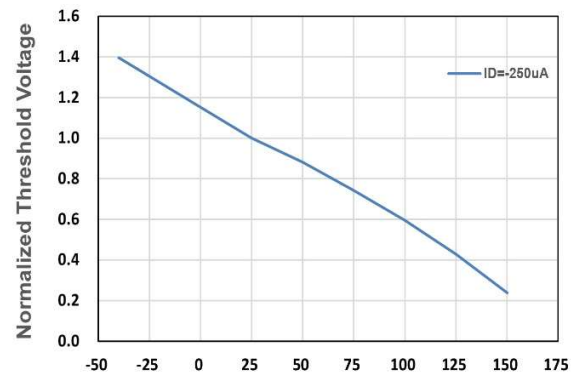
**-V<sub>DS</sub> - Drain - Source Voltage (V)**  
**Figure 1. Output Characteristics**



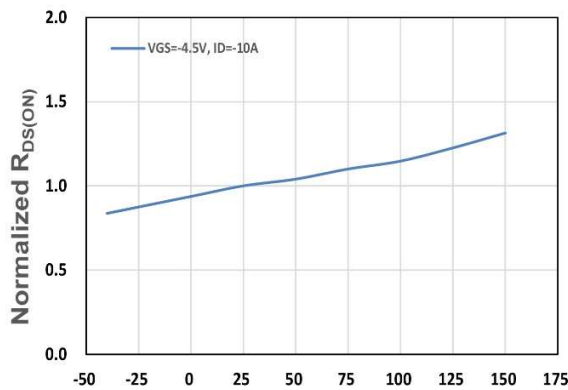
**-ID - Drain Current (A)**  
**Figure 2. On-Resistance vs. ID**



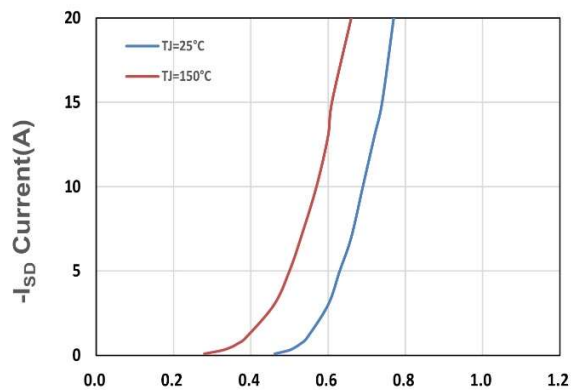
**-V<sub>GS</sub> - Gate - Source Voltage (V)**  
**Figure 3. On-Resistance vs. VGS**



**T<sub>j</sub>, Junction Temperature(°C)**  
**Figure 4. Gate Threshold Voltage**

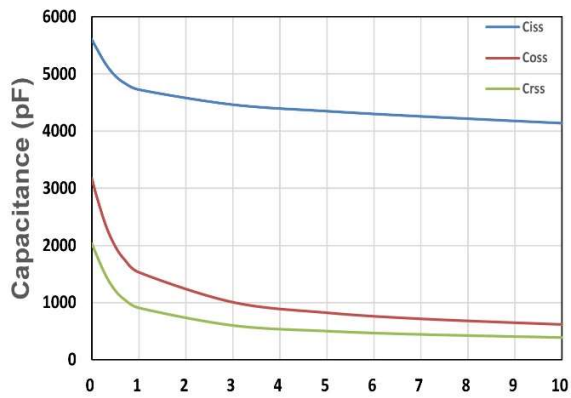


**T<sub>j</sub>, Junction Temperature(°C)**  
**Figure 5. Drain-Source On Resistance**

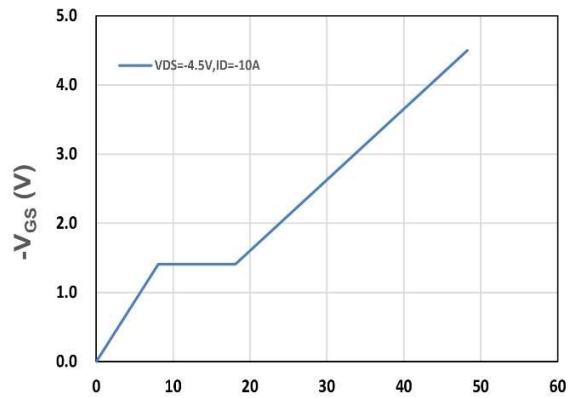


**-V<sub>SD</sub>, Source-Drain Voltage(V)**  
**Figure 6. Source-Drain Diode Forward**

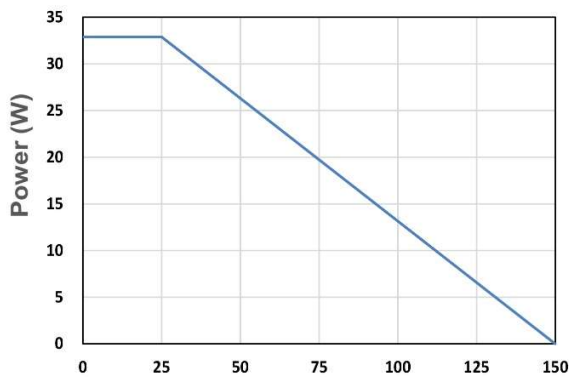
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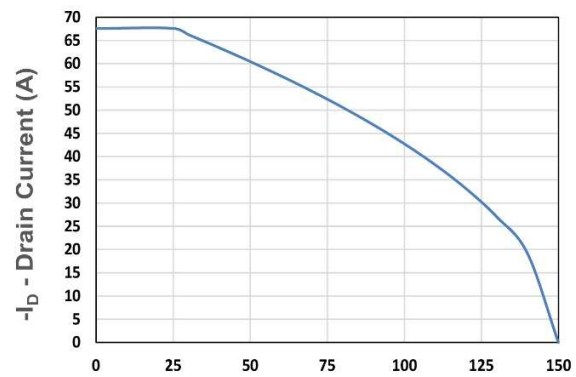
$-V_{DS}$  - Drain - Source Voltage (V)  
Figure 7. Capacitance



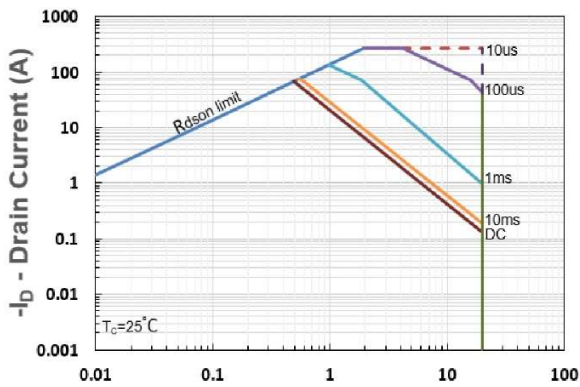
$Q_g$ , Total Gate Charge (nC)  
Figure 8. Gate Charge Characteristics



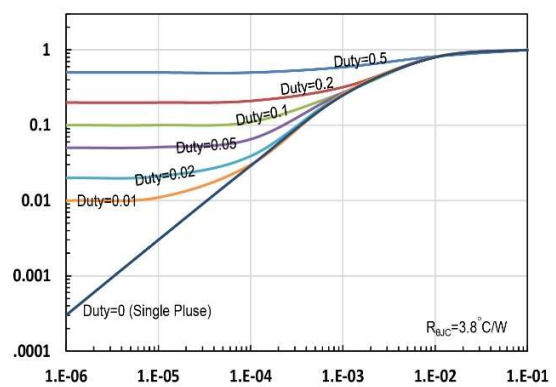
$T_c$  - Case Temperature (°C)  
Figure 9. Power Dissipation



$T_c$  - Case Temperature (°C)  
Figure 10. Drain Current



$-V_{DS}$  - Drain-Source Voltage (V)  
Figure 11. Safe Operating Area



$t_1$ , Square Wave Pulse Duration (s)  
Figure 12.  $R_{\theta JC}$  Transient Thermal Impedance